


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527567	<b>Applicant(s)/Patent Under Reexamination</b>  SUTTON ET AL.
	<b>Examiner</b>  Jaeyun Lee	<b>Art Unit</b>  1791

SEARCHED			
Class	Subclass	Date	Examiner
264	211	3/13/08	ld
264	148	11/6/2008	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
Upadated EAST serach (USPAT, US-PGPUB, EPO, JPO, DERWENT, FPRS, USOCR)	1/12/2010	/JL/
text search	1/12/2010	/JL/
Consulted Primary Examiner Jeff Aftergut	1/12/2010	/JL/

INTERFERENCE SEARCH			
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See Interference search printout		1/12/2010	/JL/

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